

Biographical Sketch

Scott Davidson

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Scott has been working in Testing for 27 years. He spent 15 years at Bell Laboratories, developing and managing IC DFT tools including fault simulation, sequential automatic test generation, and Logic BIST. He has worked at Sun Microsystems for over 10 years. He now tracks field failures of Sparc processors and develops visualization and statistical approaches to assist in detecting trends and in debugging problems.

He has been on the Program Committee of the International Test Conference since 1992, and was Program Chair in 2004 and General Chair in 2006. He has been program chair of a number of workshops, and founded several. He won the 2005 ITC Best Panel award for Test Compression Shootout. He is also the editor of The Last Byte column in IEEE Design & Test of Computers since 1996, a book review editor, and a member of the Editorial Board.

He has a B.S. From MIT, an M.S. from the University of Illinois, Champaign-Urbana, and a PhD from the University of Louisiana, all in Computer Science. He has published extensively in both microprogramming and test.